

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/683,002	BASTIAENS ET AL.	
	Examiner	Art Unit	
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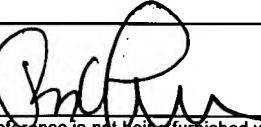
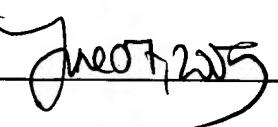
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